

# N-Channel 40-V (D-S) 175 °C MOSFET

## PRODUCT SUMMARY

| $V_{(BR)DSS}$ (V) | $r_{DS(on)}$ ( $\Omega$ ) | $I_D$ (A) | $Q_g$ (Typ.) |
|-------------------|---------------------------|-----------|--------------|
| 40                | 0.0053 at $V_{GS} = 10$ V | 110       | 95           |

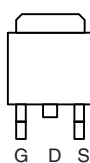
## FEATURES

- TrenchFET® Power MOSFET
- 175 °C Junction Temperature
- High Threshold Voltage at High Temperature



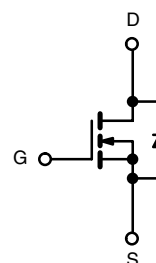
**RoHS**  
COMPLIANT

TO-263



Top View

Ordering Information: SUM110N04-05H-E3 (Lead (Pb)-free)



N-Channel MOSFET

## ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherwise noted

| Parameter                                        | Symbol                     | Limit                  | Unit |
|--------------------------------------------------|----------------------------|------------------------|------|
| Drain-Source Voltage                             | $V_{DS}$                   | 40                     | V    |
| Gate-Source Voltage                              | $V_{GS}$                   | 20                     |      |
| Continuous Drain Current ( $T_J = 175$ °C)       | $T_C = 25$ °C              | $I_D$ 110              | A    |
|                                                  | $T_C = 125$ °C             | 70                     |      |
| Pulsed Drain Current                             | $I_{DM}$                   | 300                    |      |
| Avalanche Current                                | $I_{AR}$                   | 50                     |      |
| Repetitive Avalanche Energy <sup>a</sup>         | $L = 0.1$ mH               | $E_{AR}$ 125           | mJ   |
| Maximum Power Dissipation <sup>a</sup>           | $T_C = 25$ °C              | $P_D$ 150 <sup>b</sup> | W    |
|                                                  | $T_A = 25$ °C <sup>c</sup> | 3.75                   |      |
| Operating Junction and Storage Temperature Range | $T_J, T_{stg}$             | - 55 to 175            | °C   |

## THERMAL RESISTANCE RATINGS

| Parameter           | Symbol     | Limit | Unit |
|---------------------|------------|-------|------|
| Junction-to-Ambient | $R_{thJA}$ | 40    | °C/W |
| Junction-to-Case    | $R_{thJC}$ | 1     |      |

Notes:

a. Duty cycle  $\leq 1$  %.

b. See SOA curve for voltage derating.

c. When Mounted on 1" square PCB (FR-4 material).

| SPECIFICATIONS $T_J = 25\text{ }^{\circ}\text{C}$ , unless otherwise noted                     |               |                                                                                                                                     |      |        |           |               |
|------------------------------------------------------------------------------------------------|---------------|-------------------------------------------------------------------------------------------------------------------------------------|------|--------|-----------|---------------|
| Parameter                                                                                      | Symbol        | Test Conditions                                                                                                                     | Min. | Typ.   | Max.      | Unit          |
| Static                                                                                         |               |                                                                                                                                     |      |        |           |               |
| Drain-Source Breakdown Voltage                                                                 | $V_{(BR)DSS}$ | $V_{DS} = 0\text{ V}$ , $I_D = 250\text{ }\mu\text{A}$                                                                              | 40   |        |           | V             |
| Gate-Threshold Voltage                                                                         | $V_{GS(th)}$  | $V_{DS} = V_{GS}$ , $I_D = 250\text{ }\mu\text{A}$                                                                                  | 3.4  | 3.8    | 5.0       |               |
| Gate-Body Leakage                                                                              | $I_{GSS}$     | $V_{DS} = 0\text{ V}$ , $V_{GS} = \pm 20\text{ V}$                                                                                  |      |        | $\pm 100$ | nA            |
| Zero Gate Voltage Drain Current                                                                | $I_{DSS}$     | $V_{DS} = 40\text{ V}$ , $V_{GS} = 0\text{ V}$                                                                                      |      |        | 1         | $\mu\text{A}$ |
|                                                                                                |               | $V_{DS} = 40\text{ V}$ , $V_{GS} = 0\text{ V}$ , $T_J = 125\text{ }^{\circ}\text{C}$                                                |      |        | 50        |               |
|                                                                                                |               | $V_{DS} = 40\text{ V}$ , $V_{GS} = 0\text{ V}$ , $T_J = 175\text{ }^{\circ}\text{C}$                                                |      |        | 250       |               |
| On-State Drain Current <sup>a</sup>                                                            | $I_{D(on)}$   | $V_{DS} = 5\text{ V}$ , $V_{GS} = 10\text{ V}$                                                                                      | 120  |        |           | A             |
| Drain-Source On-State Resistance <sup>a</sup>                                                  | $r_{DS(on)}$  | $V_{GS} = 10\text{ V}$ , $I_D = 30\text{ A}$                                                                                        |      | 0.0044 | 0.0053    | $\Omega$      |
|                                                                                                |               | $V_{GS} = 10\text{ V}$ , $I_D = 30\text{ A}$ , $T_J = 125\text{ }^{\circ}\text{C}$                                                  |      |        | 0.008     |               |
|                                                                                                |               | $V_{GS} = 10\text{ V}$ , $I_D = 30\text{ A}$ , $T_J = 175\text{ }^{\circ}\text{C}$                                                  |      |        | 0.0106    |               |
| Forward Transconductance <sup>a</sup>                                                          | $g_{fs}$      | $V_{DS} = 15\text{ V}$ , $I_D = 15\text{ A}$                                                                                        | 20   | 50     |           | S             |
| Dynamic <sup>b</sup>                                                                           |               |                                                                                                                                     |      |        |           |               |
| Input Capacitance                                                                              | $C_{iss}$     | $V_{GS} = 0\text{ V}$ , $V_{DS} = 25\text{ V}$ , $f = 1\text{ MHz}$                                                                 |      | 6700   |           | pF            |
| Output Capacitance                                                                             | $C_{oss}$     |                                                                                                                                     |      | 600    |           |               |
| Reverse Transfer Capacitance                                                                   | $C_{rss}$     |                                                                                                                                     |      | 320    |           |               |
| Total Gate Charge <sup>c</sup>                                                                 | $Q_g$         | $V_{DS} = 20\text{ V}$ , $V_{GS} = 10\text{ V}$ , $I_D = 50\text{ A}$                                                               |      | 95     |           | nC            |
| Gate-Source Charge <sup>c</sup>                                                                | $Q_{gs}$      |                                                                                                                                     |      | 37     |           |               |
| Gate-Drain Charge <sup>c</sup>                                                                 | $Q_{gd}$      |                                                                                                                                     |      | 21     |           |               |
| Gate Resistance                                                                                | $R_g$         | $f = 1.0\text{ MHz}$                                                                                                                |      | 1.7    |           | $\Omega$      |
| Turn-On Delay Time <sup>c</sup>                                                                | $t_{d(on)}$   | $V_{DD} = 20\text{ V}$ , $R_L = 0.4\text{ }\Omega$<br>$I_D \cong 50\text{ A}$ , $V_{GEN} = 10\text{ V}$ , $R_g = 2.5\text{ }\Omega$ |      | 20     | 30        | ns            |
| Rise Time <sup>c</sup>                                                                         | $t_r$         |                                                                                                                                     |      | 95     | 145       |               |
| Turn-Off Delay Time <sup>c</sup>                                                               | $t_{d(off)}$  |                                                                                                                                     |      | 50     | 75        |               |
| Fall Time <sup>c</sup>                                                                         | $t_f$         |                                                                                                                                     |      | 12     | 20        |               |
| Source-Drain Diode Ratings and Characteristics $T_C = 25\text{ }^{\circ}\text{C}$ <sup>b</sup> |               |                                                                                                                                     |      |        |           |               |
| Continuous Current                                                                             | $I_S$         |                                                                                                                                     |      |        | 100       | A             |
| Pulsed Current                                                                                 | $I_{SM}$      |                                                                                                                                     |      |        | 300       |               |
| Forward Voltage <sup>a</sup>                                                                   | $V_{SD}$      | $I_F = 30\text{ A}$ , $V_{GS} = 0\text{ V}$                                                                                         |      | 0.90   | 1.50      | V             |
| Reverse Recovery Time                                                                          | $t_{rr}$      | $I_F = 30\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$                                                                            |      | 40     | 60        | ns            |

Notes:

a. Pulse test; pulse width  $\leq 300\text{ }\mu\text{s}$ , duty cycle  $\leq 2\%$ .

b. Guaranteed by design, not subject to production testing.

c. Independent of operating temperature.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.